

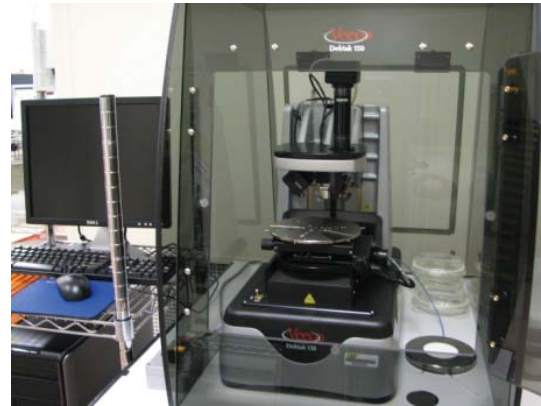
Profilometry:

Nanometer scale profile measurements for film height, roughness and stress



Allesi 4pt Probe

- Resistivity of thin films



Dektak D-150

- 54mm scan length
- 1mm max height
- Low force option
- Film Stress option



Tencor AS 200

- 10mm scan length
- +/-160um range



Dektak 3030ST

- 50mm scan length
- 130um range